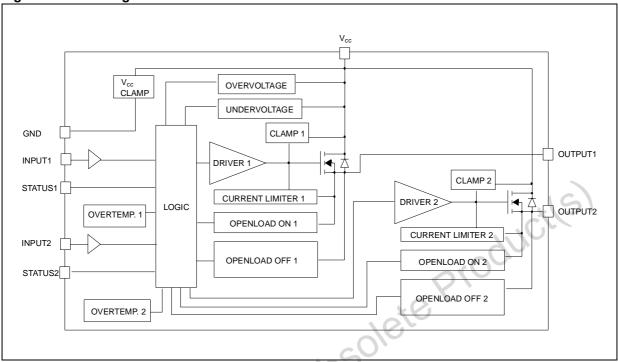
Figure 2. Block Diagram



**Table 3. Absolute Maximum Ratings** 

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	DC Supply Voltage	41	V
- V <sub>CC</sub>	Reverse DC Supply Voltage	- 0.3	V
- I <sub>GND</sub>	DC Reverse Ground Pin Current	- 200	mA
I <sub>OUT</sub>	DC Output Current	Internally Limited	А
- I <sub>OUT</sub>	Reverse DC Output Current	- 6	А
I <sub>IN</sub>	DC Input Current	+/- 10	mA
I <sub>stat</sub>	DC Status Current	+/- 10	mA
V <sub>ESD</sub>	Electrostatic Discharge (Human Body Model: R=1.5KΩ; C=100pF) - INPUT - STATUS - OUTPUT - V <sub>CC</sub>	4000 4000 5000 5000	V V V
Maximum Switching Energy  E <sub>MAX</sub> (L=1.5mH; R <sub>L</sub> =0Ω; V <sub>bat</sub> =13.5V; T <sub>jstart</sub> =150°C; I <sub>L</sub> =5A)		26	mJ
P <sub>tot</sub>	Power Dissipation T <sub>C</sub> =25°C	8.3	W
Tj	Junction Operating Temperature	Internally Limited	°C
T <sub>c</sub>	Case Operating Temperature	- 40 to 150	°C
T <sub>stg</sub>	Storage Temperature	- 55 to 150	°C

Figure 3. Configuration Diagram (Top View) & Suggested Connections for Unused and N.C. Pins

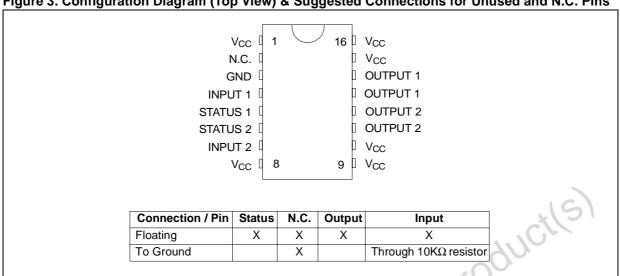
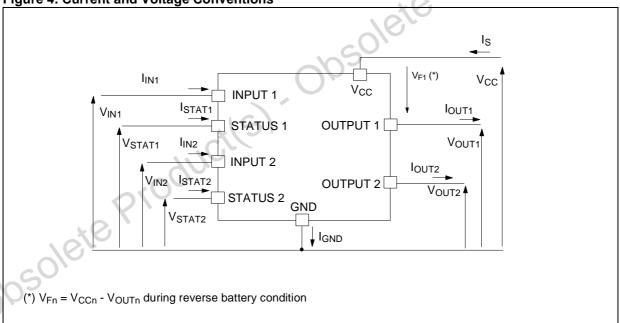


Figure 4. Current and Voltage Conventions



**Table 4. Thermal Data** 

Symbol	Parameter	Value	Unit
R <sub>thj-lead</sub>	Thermal Resistance Junction-lead	15	°C/W
R <sub>thj-amb</sub>	Thermal Resistance Junction-ambient	77 <sup>(1)</sup> 57 <sup>(2)</sup>	°C/W

Note: 1. When mounted on a standard single-sided FR-4 board with 0.5cm<sup>2</sup> of Cu (at least 35μm thick) connected to all V<sub>CC</sub> pins. Horizontal mounting and no artificial air flow.

Note: 2. When mounted on a standard single-sided FR-4 board with  $4\text{cm}^2$  of Cu (at least  $35\mu\text{m}$  thick) connected to all  $V_{CC}$  pins. Horizontal mounting and no artificial air flow.

# **ELECTRICAL CHARACTERISTICS**

(8V<V<sub>CC</sub><36V; -40°C <  $T_j$  <150°C, unless otherwise specified) (Per each channel)

## **Table 5. Power Output**

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>CC</sub> (**)	Operating Supply Voltage		5.5	13	36	V
V <sub>USD</sub> (**)	Undervoltage Shut-down		3	4	5.5	V
V <sub>OV</sub> (**)	Overvoltage Shut-down		36			V
R <sub>ON</sub>	On State Resistance	I <sub>OUT</sub> =1A; T <sub>j</sub> =25°C I <sub>OUT</sub> =1A; V <sub>CC</sub> >8V			160 320	$m\Omega$
I <sub>S</sub> (**)	Supply Current	Off State; $V_{CC}=13V$ ; $V_{IN}=V_{OUT}=0V$ Off State; $V_{CC}=13V$ ; $V_{IN}=V_{OUT}=0V$ ; $T_j=25^{\circ}C$ On State; $V_{CC}=13V$ ; $V_{IN}=5V$ ; $I_{OUT}=0A$		12 12 5	40 25 7	μΑ μΑ mA
I <sub>L(off1)</sub>	Off State Output Current	V <sub>IN</sub> =V <sub>OUT</sub> =0V	0		50	μΑ
I <sub>L(off2)</sub>	Off State Output Current	V <sub>IN</sub> =0V; V <sub>OUT</sub> =3.5V	-75		0	μΑ
I <sub>L(off3)</sub>	Off State Output Current	V <sub>IN</sub> =V <sub>OUT</sub> =0V; V <sub>CC</sub> =13V; T <sub>j</sub> =125°C			5	μΑ
I <sub>L(off4)</sub>	Off State Output Current	$V_{IN}=V_{OUT}=0V; V_{CC}=13V; T_j=25^{\circ}C$			3	μΑ

Note: (\*\*) Per device.

# Table 6. Protection (see note 1)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
T <sub>TSD</sub>	Shut-down Temperature		150	175	200	°C
T <sub>R</sub>	Reset Temperature	9	135			°C
T <sub>hyst</sub>	Thermal Hysteresis		7	15		°C
t <sub>SDL</sub>	Status Delay in Overload Conditions	$T_j > T_{TSD}$			20	μs
1	Current limitation		3.5	5	7.5	Α
l <sub>lim</sub>	Current inmation	5.5V <v<sub>CC&lt;36V</v<sub>			7.5	Α
V <sub>demag</sub>	Turn-off Output Clamp Voltage	I <sub>OUT</sub> =1A; L=6mH	V <sub>CC</sub> - 41	V <sub>CC</sub> -48	V <sub>CC</sub> - 55	V

Note: 1. To ensure long term reliability under heavy overload or short circuit conditions, protection and related diagnostic signals must be used together with a proper software strategy. If the device is subjected to abnormal conditions, this software must limit the duration and number of activation cycles

# Table 7. V<sub>CC</sub> - Output Diode

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
VF	Forward on Voltage	-I <sub>OUT</sub> =0.5A; T <sub>j</sub> =150°C			0.6	V

# **ELECTRICAL CHARACTERISTICS** (continued)

## Table 8. Status Pin

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>STAT</sub>	Status Low Output Voltage	I <sub>STAT</sub> = 1.6 mA			0.5	V
I <sub>LSTAT</sub>	Status Leakage Current	Normal Operation; V <sub>STAT</sub> = 5V			10	μΑ
C <sub>STAT</sub>	Status Pin Input Capacitance	Normal Operation; V <sub>STAT</sub> = 5V			100	pF
Vac	Status Clamp Voltage	I <sub>STAT</sub> = 1mA	6	6.8	8	V
V <sub>SCL</sub>	Status Clamp Voltage	I <sub>STAT</sub> = - 1mA		-0.7		V

# Table 9. Switching (V<sub>CC</sub>=13V)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
t <sub>d(on)</sub>	Turn-on Delay Time	$R_L$ =13 $\Omega$ from $V_{IN}$ rising edge to $V_{OUT}$ =1.3 $V$		30	Cil	μs
t <sub>d(off)</sub>	Turn-off Delay Time	$R_L$ =13 $\Omega$ from $V_{IN}$ falling edge to $V_{OUT}$ =11.7 $V$		30		μs
dV <sub>OUT</sub> /dt <sub>(on)</sub>	Turn-on Voltage Slope	$R_L$ =13 $\Omega$ from $V_{OUT}$ =1.3 $V$ to $V_{OUT}$ =10.4 $V$	6/	See relative diagram		V/μs
dV <sub>OUT</sub> /dt <sub>(off)</sub>	Turn-off Voltage Slope	$R_L$ =13 $\Omega$ from $V_{OUT}$ =11.7 $V$ to $V_{OUT}$ =1.3 $V$		See relative diagram		V/μs

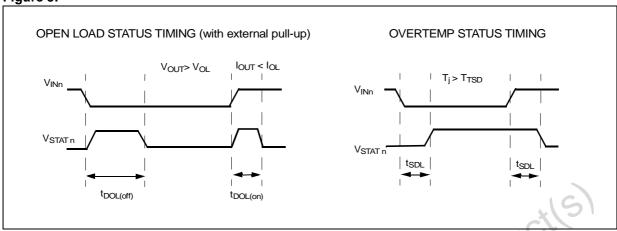
# **Table 10. Openload Detection**

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
1	Openload ON State	V <sub>IN</sub> =5V	20	40	80	mA
I <sub>OL</sub>	Detection Threshold	VIN=3 V	20	40	60	IIIA
<b>4</b>	Openload ON State	Jane OA			200	
t <sub>DOL(on)</sub>	Detection Delay	I <sub>OUT</sub> =0A			200	μs
	Openload OFF State					
$V_{OL}$	Voltage Detection	V <sub>IN</sub> =0V	1.5	2.5	3.5	V
	Threshold					
tnoi (off)	Openload Detection Delay				1000	μs
t <sub>DOL(off)</sub>	at Turn Off					μο

# Table 11. Logic Input

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>IL</sub>	Input Low Level				1.25	V
I <sub>IL</sub>	Low Level Input Current	V <sub>IN</sub> = 1.25V	1			μΑ
V <sub>IH</sub>	Input High Level		3.25			V
l <sub>IH</sub>	High Level Input Current	V <sub>IN</sub> = 3.25V			10	μΑ
V <sub>I(hyst)</sub>	Input Hysteresis Voltage		0.5			V
\/	Innut Clamp Voltage	I <sub>IN</sub> = 1mA	6	6.8	8	V
V <sub>ICL</sub>	Input Clamp Voltage	I <sub>IN</sub> = -1mA		-0.7		V

Figure 5.



**Table 12. Truth Table** 

CONDITIONS	INPUT	OUTPUT	SENSE
Normal Operation	L H	L H	H H
Current Limitation	L H H	X X	$ H $ $ (T_j < T_{TSD}) H $ $ (T_j > T_{TSD}) L $
Overtemperature	L	L L	H L
Undervoltage	LS	L L	X X
Overvoltage	9/7/0 F	L L	H H
Output Voltage > VoL	L H	H H	L H
Output Current < I <sub>OL</sub>	L H	L H	H L

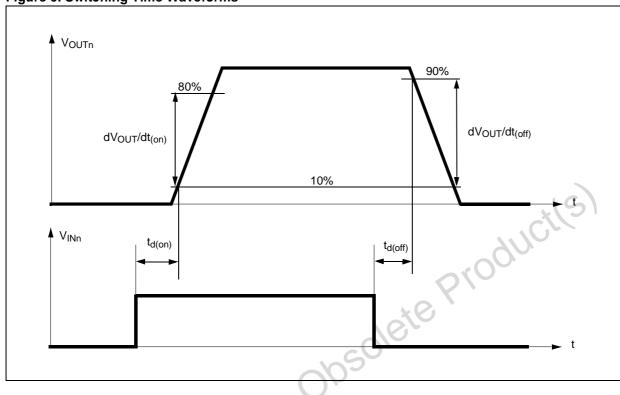


Figure 6. Switching Time Waveforms

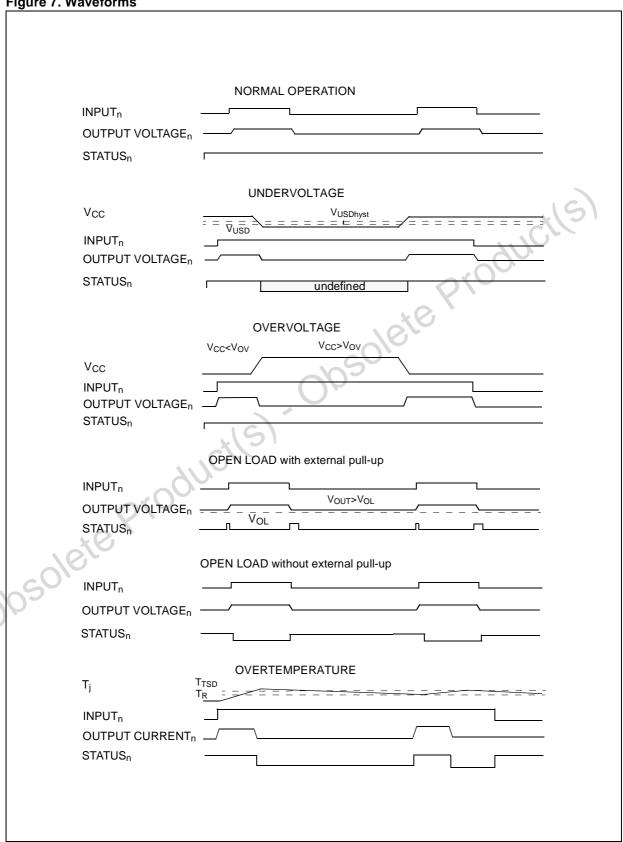
Table 13. Electrical Transient Requirements On V<sub>CC</sub> Pin

ISO T/R 7637/1		1(5)	TEST LEVELS		
Test Pulse	I	II	III	IV	Delays and Impedance
1	-25 V	-50 V	-75 V	-100 V	2 ms 10 Ω
2	+25 V	+50 V	+75 V	+100 V	$0.2~\text{ms}~10~\Omega$
3a	-25 V	-50 V	-100 V	-150 V	0.1 μs 50 Ω
3b	+25 V	+50 V	+75 V	+100 V	0.1 μs 50 Ω
4	-4 V	-5 V	-6 V	-7 V	100 ms, 0.01 $\Omega$
5	+26.5 V	+46.5 V	+66.5 V	+86.5 V	400 ms, 2 Ω

ISO T/R 7637/1	TEST LEVELS RESULTS						
Test Pulse	ļ	II	III	IV			
1	С	С	С	С			
2	С	С	С	С			
3a	С	С	С	С			
3b	С	С	С	С			
4	С	С	С	С			
5	С	E	E	E			

CLASS	CONTENTS
С	All functions of the device are performed as designed after exposure to disturbance.
Е	One or more functions of the device is not performed as designed after exposure and cannot be returned to proper operation without replacing the device.





+5V +5V +5V Vcc Rprot STATUS1  $D_{ld}$ R<sub>prot</sub> μС INPUT1 OUTPUT<sup>-</sup> Rprot STATUS2 INPUT2 OUTPUT2 GND VGNE

Figure 8. Application Schematic

# GND PROTECTION NETWORK AGAINST REVERSE BATTERY

Solution 1: Resistor in the ground line (R<sub>GND</sub> only). This can be used with any type of load.

The following is an indication on how to dimension the  $R_{\mbox{\footnotesize{GND}}}$  resistor.

- 1)  $R_{GND} \le 600 \text{mV} / I_{S(on)max}$
- 2)  $R_{GND} \ge (-V_{CC}) / (-I_{GND})$

where -I<sub>GND</sub> is the DC reverse ground pin current and can be found in the absolute maximum rating section of the device's datasheet.

Power Dissipation in  $R_{GND}$  (when  $V_{CC}\!\!<\!\!0$ : during reverse battery situations) is:

 $P_D = (-V_{CC})^2 / R_{GND}$ 

This resistor can be shared amongst several different HSD. Please note that the value of this resistor should be calculated with formula (1) where  $I_{S(on)max}$  becomes the sum of the maximum on-state currents of the different devices.

Please note that if the microprocessor ground is not common with the device ground then the  $R_{GND}$  will produce a shift  $(I_{S(on)max} \ ^* R_{GND})$  in the input thresholds and the status output values. This shift will vary depending on how many devices are ON in the case of several high side drivers sharing the same  $R_{GND}.$ 

If the calculated power dissipation leads to a large resistor or several devices have to share the same resistor then the ST suggests to utilize Solution 2 (see below).

Solution 2: A diode (D<sub>GND</sub>) in the ground line.

A resistor (RGND=1k $\Omega$ ) should be inserted in parallel to DGND if the device will be driving an inductive load.

This small signal diode can be safely shared amongst several different HSD. Also in this case, the presence of the ground network will produce a shift ( $\simeq 600$ mV) in the input threshold and the status output values if the microprocessor ground is not common with the device ground. This shift will not vary if more than one HSD

shares the same diode/resistor network.

Series resistor in INPUT and STATUS lines are also required to prevent that, during battery voltage transient, the current exceeds the Absolute Maximum Rating.

Safest configuration for unused INPUT and STATUS pin is to leave them unconnected.

### LOAD DUMP PROTECTION

 $D_{ld}$  is necessary (Voltage Transient Suppressor) if the load dump peak voltage exceeds  $V_{CC}$  max DC rating. The same applies if the device will be subject to transients on the  $V_{CC}$  line that are greater than the ones shown in the ISO T/R 7637/1 table.

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### μC I/Os PROTECTION:

If a ground protection network is used and negative transient are present on the  $V_{CC}$  line, the control pins will be pulled negative. ST suggests to insert a resistor ( $R_{prot}$ ) in line to prevent the  $\mu C$  I/Os pins to latch-up.

The value of these resistors is a compromise between the leakage current of  $\mu C$  and the current required by the HSD I/Os (Input levels compatibility) with the latch-up limit of  $\mu C$  I/Os.

- $V_{CCpeak}/I_{latchup} \le R_{prot} \le (V_{OH\mu C}-V_{IH}-V_{GND}) / I_{IHmax}$  Calculation example:

For V<sub>CCpeak</sub>= - 100V and I<sub>latchup</sub>  $\geq$  20mA; V<sub>OHµC</sub>  $\geq$  4.5V  $5k\Omega \leq R_{prot} \leq 65k\Omega$ .

Recommended  $R_{prot}$  value is  $10k\Omega$ .

### **OPEN LOAD DETECTION IN OFF STATE**

Off state open load detection requires an external pull-up resistor ( $R_{PU}$ ) connected between OUTPUT pin and a

positive supply voltage ( $V_{PU}$ ) like the +5V line used to supply the microprocessor.

The external resistor has to be selected according to the following requirements:

- no false open load indication when load is connected: in this case we have to avoid V<sub>OUT</sub> to be higher than V<sub>Olmin</sub>; this results in the following condition V<sub>OUT</sub>=(V<sub>PU</sub>/(R<sub>L</sub>+R<sub>PU</sub>))R<sub>L</sub><V<sub>Olmin</sub>.
- 2) no misdetection when load is disconnected: in this case the  $V_{OUT}$  has to be higher than  $V_{OLmax}$ ; this results in the following condition  $R_{PU}$ <( $V_{PU}$ - $V_{OLmax}$ )/  $I_{L(off2)}$ .

Because  $I_{s(OFF)}$  may significantly increase if  $V_{out}$  is pulled high (up to several mA), the pull-up resistor  $R_{PU}$  should be connected to a supply that is switched OFF when the module is in standby.

The values of  $V_{OLmin}$ ,  $V_{OLmax}$  and  $I_{L(off2)}$  are available in the Electrical Characteristics section.

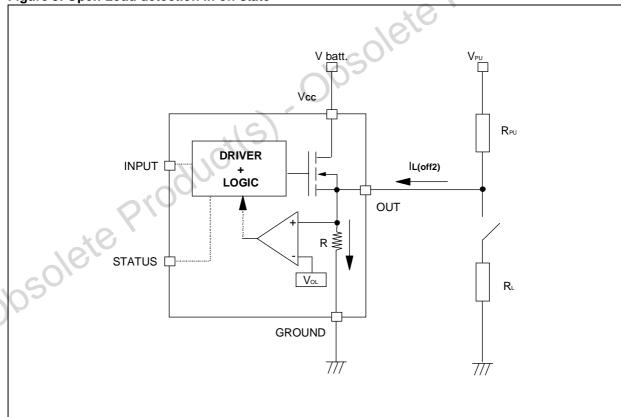


Figure 9. Open Load detection in off state

Figure 10. Off State Output Current

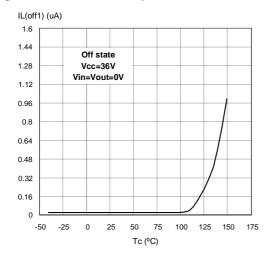


Figure 13. High Level Input Current lih (uA)

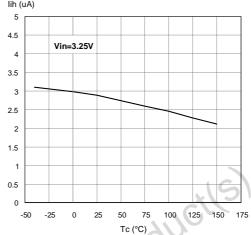


Figure 11. Input Clamp Voltage

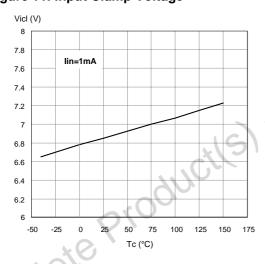


Figure 14. Status Leakage Current

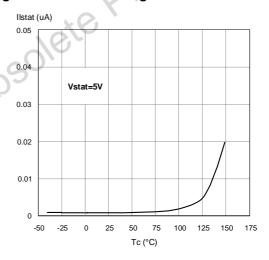


Figure 12. Status Low Output Voltage

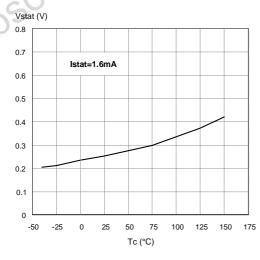


Figure 15. Status Clamp Voltage

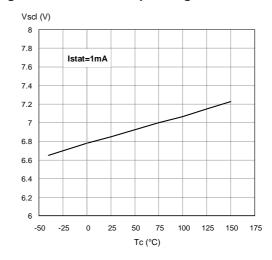


Figure 16. On State Resistance Vs T<sub>case</sub>

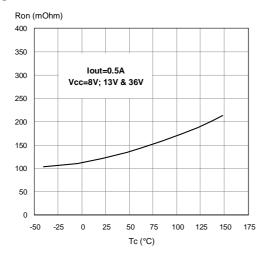


Figure 17. Openload On State Detection
Threshold

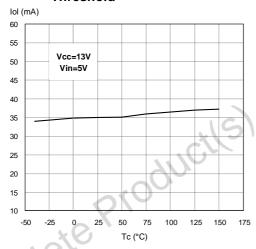


Figure 18. Input High Level

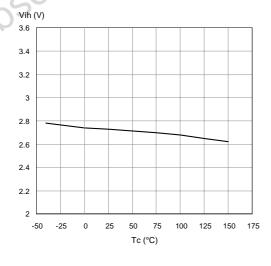


Figure 19. On State Resistance Vs V<sub>CC</sub>

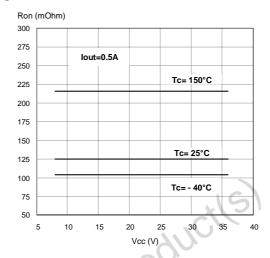


Figure 20. Openload Off State Detection Threshold

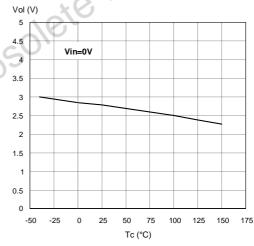


Figure 21. Input Low Level

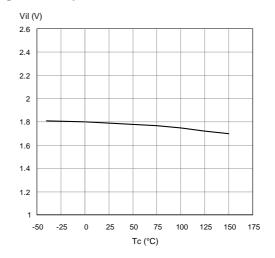


Figure 22. Input Hysteresis Voltage

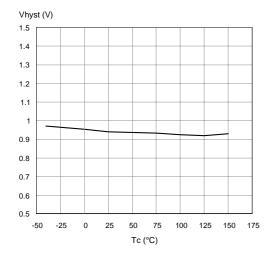


Figure 25. Overvoltage Shutdown

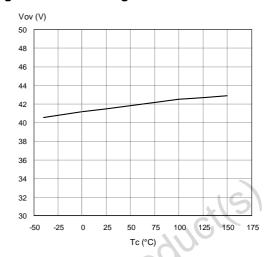


Figure 23. Turn-on Voltage Slope

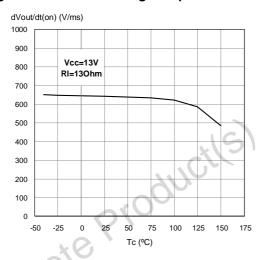


Figure 26. Turn-off Voltage Slope

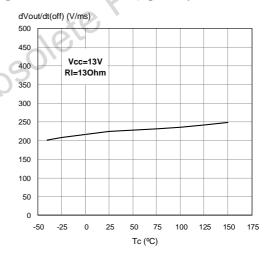
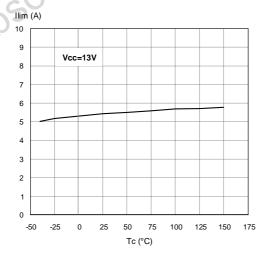


Figure 24. I<sub>LIM</sub> Vs T<sub>case</sub>



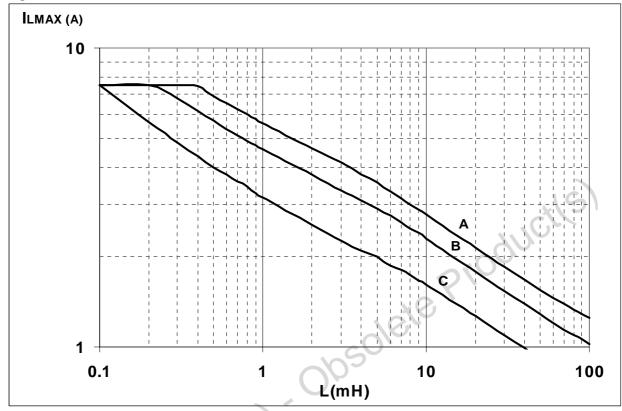
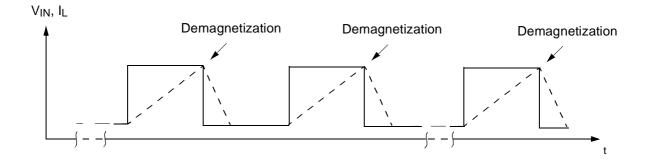


Figure 27. Maximum turn off current versus load inductance

A = Single Pulse at T<sub>Jstart</sub>=150°C B= Repetitive pulse at T<sub>Jstart</sub>=100°C C= Repetitive Pulse at T<sub>Jstart</sub>=125°C

Conditions: V<sub>CC</sub>=13.5V Values are generated with  $R_L=0\Omega$ 

In case of repetitive pulses,  $T_{jstart}$  (at beginning of each demagnetization) of every pulse must not exceed the temperature specified above for curves B and C.



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## PowerSO-10™ Thermal Data

Figure 28. SO-16 PC Board

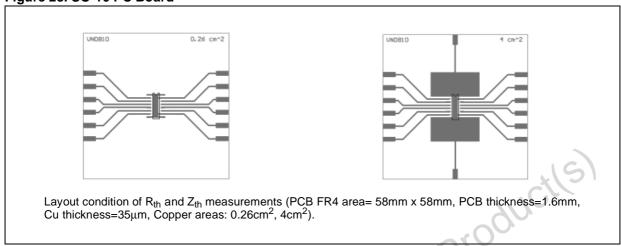


Figure 29.  $R_{thj\text{-}amb}$  Vs PCB copper area in open box free air condition

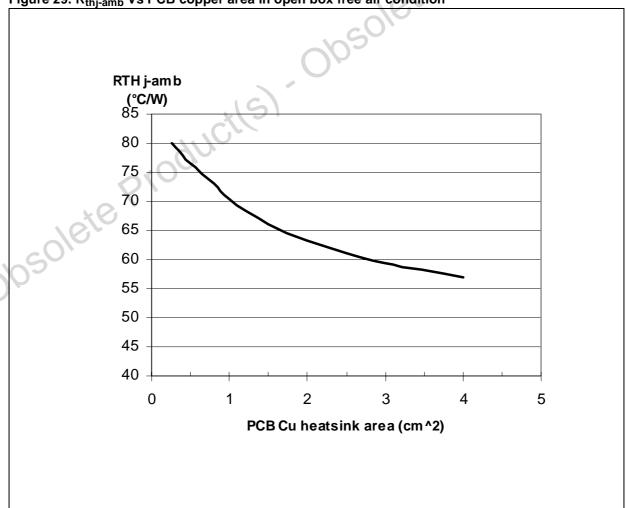


Figure 30. SO-16 Thermal Impedance Junction Ambient Single Pulse

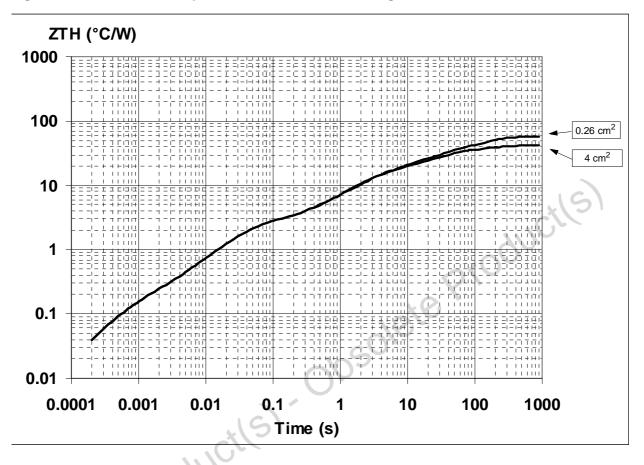
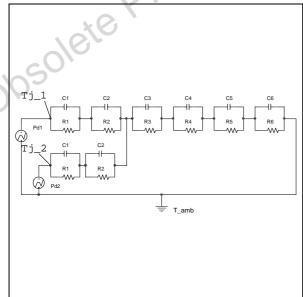


Figure 31. Thermal fitting model of a double channel HSD in SO-16



# Pulse calculation formula

$$\begin{split} Z_{TH\delta} &= R_{TH} \cdot \delta + Z_{THtp} (1 - \delta) \\ \text{where} \quad \delta &= t_p / T \end{split}$$

**Table 14. Thermal Parameter** 

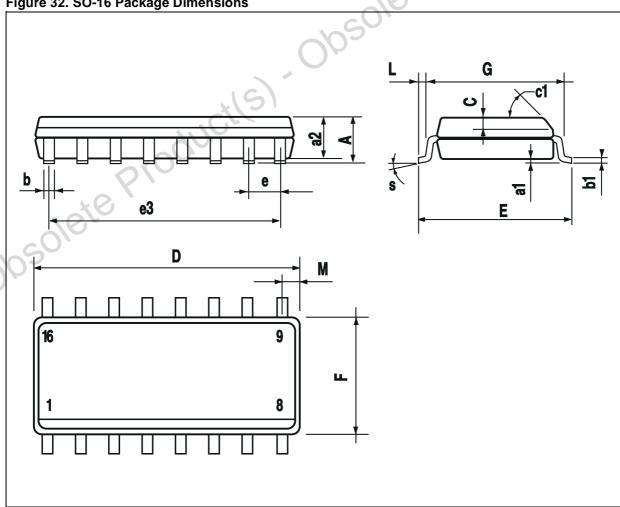
Area/island (cm <sup>2</sup> )	0.5	4
R1 (°C/W)	0.35	
R2 (°C/W)	1.8	
R3 ( °C/W)	4.5	
R4 (°C/W)	10	
R5 (°C/W)	16	
R6 (°C/W)	48	25
C1 (W.s/°C)	0.0001	
C2 (W.s/°C)	7.00E-04	
C3 (W.s/°C)	6.00E-03	
C4 (W.s/°C)	0.2	
C5 (W.s/°C)	0.7	
C6 (W.s/°C)	2	4

# **PACKAGE MECHANICAL**

Table 15. SO-16 Mechanical Data

Cumbal		millimeters	
Symbol	Min	Тур	Max
A			1.75
a1	0.1		0.2
a2			1.65
b	0.35		0.46
b1	0.19		025
С		0.5	
c1		45° (typ.)	_
D	9.8		10
Е	5.8		6.2
е		1.27	
e3		8.89	
F	3.8		4.0
G	4.6		5.3
L	0.5		1.27
M			0.62
S	·	8° (max.)	· ·

Figure 32. SO-16 Package Dimensions



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Figure 33. SO-16 Suggested Pad Layout And Tube Shipment (no suffix)

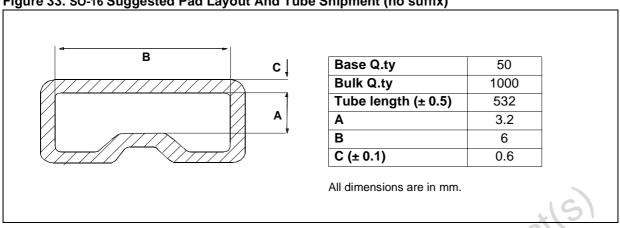
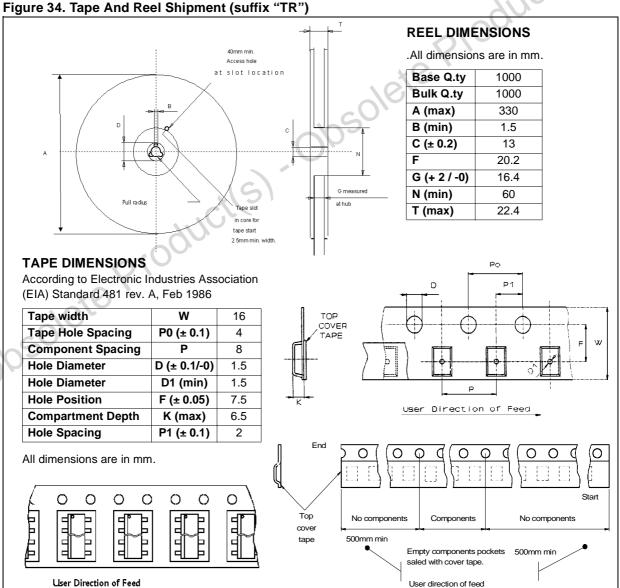


Figure 34. Tape And Reel Shipment (suffix "TR")



### **REVISION HISTORY**

Date	Revision	Description of Changes
Oct. 2004	1	- First Issue





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